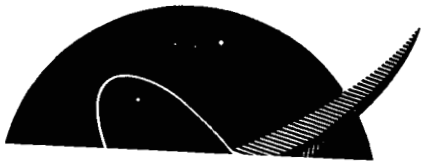

EVALUATION PROGRAM

for

SECONDARY SPACECRAFT CELLS

ACCEPTANCE TEST

OF

SONOTONE CORPORATION

5.0 AMPERE-HOUR NICKEL CADMIUM CELLS

prepared for

GODDARD SPACE FLIGHT CENTER

CONTRACT W11,252B

QUALITY EVALUATION LABORATORY

NAD CRANE, INDIANA

QUALITY EVALUATION LABORATORY
UNITED STATES NAVAL AMMUNITION DEPOT
CRANE, INDIANA

EVALUATION PROGRAM
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ACCEPTANCE TEST
OF
SONOTONE CORPORATION
5.0 AMPERE-HOUR NICKEL CADMIUM CELLS

QE/C 65-583 2 SEPTEMBER 1965

PREPARED UNDER THE DIRECTION OF

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Enclosure (1)

REPORT BRIEF

SONOTONE FIVE AMPERE-HOUR NICKEL CADMIUM SECONDARY SPACECRAFT CELLS

Ref: (a) National Aeronautics and Space Administration Purchase Order Number W11,252B
(b) NASA ltr BRA/VBK/pad of 25 September 1961 w/BUWEPS first end FQ-1:WSK of 2 October 1961 to CO NAD Crane
(c) Preliminary Work Statement for Battery Evaluation Program of 25 August 1961

I. TEST ASSIGNMENT BRIEF.

A. In compliance with references (a) and (b), evaluation of Sonotone Corporation five ampere-hour nickel cadmium secondary spacecraft cells was begun according to the program outline of reference (c).

B. The object of this evaluation program is to gather specific information concerning secondary spacecraft cells. Information concerning performance characteristics and limitations, including cycle life under various electrical and environmental conditions, will be of interest to power systems designers and users. Cell weaknesses, including cause of failure of present designs, will be of interest to suppliers as a guide to product improvement.

C. Forty cells were purchased from Sonotone Corporation, Elmsford, New York by National Aeronautics and Space Administration (NASA). These cells are rated at five ampere-hours by the manufacturer and are similar to those used in the Tiros satellite program.

II. CONCLUSIONS.

A. From the results of this test, it can be concluded that:

1. The ceramic seals of these cells manufactured by Sonotone Corporation are satisfactory as evidenced by no leakers out of the 40 cells tested.

2. The capacity of the cells was in the acceptable range of 5.05 to 6.80 ampere-hours to 1.00 volt.

III. RECOMMENDATIONS.

A. It is recommended that these Sonotone Corporation 5.0 ampere-hour cells be accepted on the basis of the acceptance test results.

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RESULTS OF ACCEPTANCE TESTS

OF

FIVE AMPERE-HOUR NICKEL CADMIUM SECONDARY SPACECRAFT CELLS

MANUFACTURED BY

SONOTONE CORPORATION

I. INTRODUCTION.

A. On 27 June 1965, this activity began acceptance tests on 40 cells. These tests were completed on 30 July 1965.

II. TEST CONDITIONS.

A. All acceptance tests were performed at an ambient temperature between 23° C and 27° C at existing relative humidity and atmospheric pressure, and consisted of the following:

1. Phenolphthalein Leak Test.
2. Capacity Test.
3. Cell Short Test.
4. Immersion Seal Test.
5. Overcharge Test.
6. Internal Resistance Test.
7. Immersion Seal Test.

B. All charging and discharging was done at constant current (± 5 percent). Cells were charged in series but were discharged individually.

III. CELL IDENTIFICATION AND DESCRIPTION.

A. The cells were identified by the manufacturer's serial numbers which were from A2410 to A2481 although not consecutively.

B. The five ampere-hour "F" cell is cylindrical with an average diameter of 1.306 inches and an average overall length of 3.624 inches including the positive terminal. The average weight was 263.3 grams. Figure 1 is a photograph of a Sonotone Corporation five ampere-hour "F" cell.

C. The cell container or can, and the cell cover are made of cold rolled steel. A stainless steel tab, welded to the cover, serves as contact for the negative terminal. The positive terminal is solder type extension of the positive plate tab through the center of the cover. The positive terminal is insulated from the "negative" cover by a ceramic seal. Two crimp rings, about 1/32 inch deep, are located about 7/8 inch from each end of the cell. These evidently tighten the element to withstand vibration.

D. These cells, rated by the manufacturer at five ampere-hours, were supplied in a partially discharged condition and will be tested with the stabistor charge control principle.

IV. TEST PROCEDURE AND RESULTS.

A. Phenolphthalein Leak Test:

1. The phenolphthalein leak test is a determination of the condition of the welds and ceramic seal on receipt of the cells. The test was performed with a phenolphthalein spray indicator solution of one-half of one percent concentration.

2. There were no signs of leakage on any of the 40 cells subjected to the leak test.

B. Capacity Test:

1. The capacity test is a determination of the cell capacity at the c/2 discharge rate, where c is the manufacturer's rated capacity, to a cutoff voltage of 1.00 volt per cell. The discharge was made after a 1-hour open circuit period following the 16-hour charge at the c/10 rate. A total of three capacity checks were made at this activity. The cells were discharged individually, but were recharged in series.

2. Since no capacity data was submitted by the manufacturer it was not possible to compare the manufacturer's capacity values with those of this activity. The individual cell capacities ranged from 5.05 to 6.80 ampere-hours for an average of 6.10 ampere-hours to 1.00 volt. The cell capacities are tabulated in Table I. Characteristic 2-hour rate discharge curves are shown in Figure 2.

C. Cell Short Test:

1. The cell short test is a means of detecting slight shorting conditions which may exist because of imperfections in the insulating materials, or damage to element in handling or assembly.

2. Following completion of the third capacity discharge test, each individual cell was loaded with a resistor of value giving a

c/1 to c/5 discharge rate and allowed to stand 16 hours with the resistor acting as a shorting device. At the end of 16 hours, the resistors were removed and the cells were placed on open circuit stand for 24 hours. Any cell whose voltage did not recover to 1.15 volts or higher after the 24-hour open circuit stand was rejected.

3. The open circuit cell voltages, 24 hours after removal of the shorting resistors, ranged from 1.20 to 1.25 volts for an average of 1.22 volts.

4. There were no rejects of any of the cells subjected to the cell short test. The voltage values for the 40 accepted cells are shown in Table I.

D. Immersion Seal Test:

1. The immersion seal test is a means of detecting leakage of a seal or weld. The test was performed before and after the overcharge sequence to determine the presence and cause of leaks.

2. The cells were placed under water in a bell jar container. A vacuum of 20 inches of mercury was held for 3 minutes. Cells discharging a steady stream of bubbles were considered rejects.

3. There were no rejects in the 40 cells subjected to the immersion seal test.

E. Overcharge Test:

1. The overcharge tests were performed to determine the steady state voltage at specified rates. The test specified a series of constant current charges at c/20, c/10 and c/5 rates, for a minimum of 48 hours at each charge rate or until the increase of the "on charge" voltage was less than 10 millivolts per day.

2. The cells were monitored hourly throughout the test. Charging was to be discontinued on cells which exceeded 1.50 volts while on charge. There was no need to remove any cells from the charging sequence.

3. The steady state voltage of each cell at the end of each 48-hour charge rate test is shown in Table I. Characteristic overcharge voltage curves are shown in Figure 3.

F. Internal Resistance Test:

1. This test was performed to determine the internal resistance of the cells.

2. At the completion of the overcharge test; the cells were returned to the c/20 charging rate and given a short pulse (5 - 10 seconds) at a rate of c in amperes. The cell voltages, V1, immediately prior to the pulse; and V2, 5 milliseconds after the pulse, were read on a suitable recording instrument. A CEC high speed oscillograph recorder (28.8 inches of tape per second) was used. The internal resistance of the cell in ohms was calculated according to the following formula:

$$R = \frac{V2 - V1}{Ic - Ic/20}$$

V1 and V2 are in volts, Ic and Ic/20 are in amperes.

3. The internal resistance value for each cell is shown in Table I. The values range from 4.21 milliohms to 8.42 milliohms.

TABLE I

CELL NUMBER	DIAMETER (INCHES)	LENGTH (INCHES)	WEIGHT (GRAMS)	CAPACITY TEST (A.H.)	CAPACITY TEST (A.H.)	CAPACITY TEST (A.H.)	CELL SHORT TEST (VOLTS)	IMMERSION SEAL TEST	OVERCHARGE c/20 (VOLTS)	OVERCHARGE c/10 (VOLTS)	OVERCHARGE c/5 (VOLTS)	INTERNAL RESISTANCE (MILLIOHMS)	IMMERSION SEAL TEST
A2410	1.307	3.644	240.6	5.92	5.20	4.68	1.21	O.K.	1.41	1.41	1.40	6.32	O.K.
A2411	1.300	3.648	229.1	5.13	5.00	5.00	1.24	O.K.	1.45	1.48	1.50	6.32	O.K.
A2413	1.300	3.620	235.3	6.20	5.88	6.28	1.24	O.K.	1.42	1.43	1.43	6.32	O.K.
A2414	1.300	3.625	236.5	6.18	5.88	6.04	1.24	O.K.	1.40	1.42	1.42	6.32	O.K.
A2415	1.304	3.640	236.9	6.18	6.00	5.75	1.23	O.K.	1.44	1.46	1.48	6.32	O.K.
A2419	1.310	3.631	237.4	6.04	5.55	5.75	1.22	O.K.	1.40	1.41	1.42	8.42	O.K.
A2420	1.308	3.627	237.3	6.38	6.00	6.16	1.22	O.K.	1.40	1.42	1.42	8.42	O.K.
A2422	1.304	3.655	243.9	6.13	5.30	4.50	1.25	O.K.	1.40	1.40	1.40	8.42	O.K.
A2423	1.304	3.615	235.1	5.70	5.33	5.46	1.23	O.K.	1.40	1.42	1.42	6.32	O.K.
A2424	1.300	3.650	233.2	5.30	5.00	5.28	1.24	O.K.	1.41	1.42	1.42	4.21	O.K.
A2426	1.305	3.625	233.0	5.92	5.45	5.08	1.22	O.K.	1.41	1.42	1.41	6.32	O.K.
A2427	1.303	3.629	237.0	6.00	5.05	4.38	1.25	O.K.	1.40	1.40	1.40	4.21	O.K.
A2430	1.300	3.650	235.2	5.93	5.08	4.78	1.24	O.K.	1.39	1.40	1.40	6.32	O.K.
A2431	1.312	3.635	241.2	5.63	5.13	5.35	1.23	O.K.	1.40	1.41	1.41	6.32	O.K.
A2432	1.303	3.615	238.8	6.38	6.20	5.95	1.22	O.K.	1.43	1.45	1.46	6.32	O.K.
A2434	1.300	3.625	237.1	5.93	5.25	5.50	1.24	O.K.	1.39	1.41	1.42	6.32	O.K.
A2435	1.300	3.585	234.3	6.43	6.25	6.46	1.23	O.K.	1.40	1.43	1.44	6.32	O.K.
A2437	1.312	3.638	240.0	6.05	5.93	5.80	1.23	O.K.	1.40	1.41	1.44	4.21	O.K.
A2442	1.304	3.615	236.4	6.33	6.30	6.05	1.21	O.K.	1.39	1.40	1.44	4.21	O.K.
A2443	1.305	3.600	237.0	5.00	5.05	4.75	1.23	O.K.	1.40	1.44	1.50	6.32	O.K.

TABLE I (Contd)

CELL NUMBER	DIAMETER (INCHES)	LENGTH (INCHES)	WEIGHT (GRAMS)	CAPACITY TEST (A.H.)	CAPACTTY TEST (A.H.)	CAPACITY TEST (A.H.)	CELL SHORT TEST (VOLTS)	IMMERSION SEAL TEST	OVERCHARGE c/20 (VOLTS)	OVERCHARGE c/10 (VOLTS)	OVERCHARGE c/5 (VOLTS)	INTERNAL RESISTANCE (MILLIOHMS)	IMMERSION SEAL TEST
A2444	1.308	3.605	232.4	6.20	6.05	5.70	1.21	O.K.	1.40	1.42	1.46	6.32	O.K.
A2446	1.305	3.630	236.1	6.08	6.08	6.05	1.23	O.K.	1.44	1.48	1.50	4.21	O.K.
A2448	1.315	3.615	230.2	6.20	5.95	5.25	1.21	O.K.	1.40	1.40	1.43	6.32	O.K.
A2454	1.312	3.625	231.7	5.83	5.95	5.75	1.23	O.K.	1.40	1.40	1.42	6.32	O.K.
A2456	1.310	3.625	234.0	6.25	5.92	5.67	1.20	O.K.	1.41	1.42	1.42	6.32	O.K.
A2457	1.308	3.616	238.5	6.33	5.95	5.70	1.20	O.K.	1.43	1.44	1.43	6.32	O.K.
A2458	1.300	3.620	233.6	6.00	5.80	5.45	1.21	O.K.	1.39	1.39	1.41	6.32	O.K.
A2460	1.305	3.625	237.0	6.20	6.08	5.80	1.22	O.K.	1.39	1.40	1.43	8.42	O.K.
A2461	1.305	3.615	237.9	5.75	5.13	4.55	1.24	O.K.	1.39	1.40	1.41	8.42	O.K.
A2465	1.300	3.610	233.9	6.58	6.38	6.13	1.21	O.K.	1.40	1.42	1.47	6.32	O.K.
A2467	1.305	3.610	237.5	6.25	5.80	5.30	1.21	O.K.	1.39	1.39	1.41	8.42	O.K.
A2468	1.305	3.625	233.8	6.30	6.08	5.83	1.21	O.K.	1.39	1.42	1.50	6.32	O.K.
A2469	1.305	3.625	238.9	6.80	6.70	6.50	1.20	O.K.	1.43	1.44	1.46	4.21	O.K.
A2472	1.308	3.620	234.5	6.20	6.08	5.80	1.23	O.K.	1.39	1.41	1.45	6.32	O.K.
A2473	1.308	3.618	240.7	6.58	6.30	5.95	1.20	O.K.	1.42	1.42	1.42	6.32	O.K.
A2474	1.303	3.620	234.7	6.33	6.18	5.93	1.22	O.K.	1.39	1.41	1.45	8.42	O.K.
A2478	1.308	3.620	237.2	6.20	5.70	5.30	1.21	O.K.	1.41	1.41	1.41	6.32	O.K.
A2479	1.308	3.621	240.9	5.95	6.58	6.43	1.22	O.K.	1.42	1.42	1.43	6.32	O.K.
A2480	1.312	3.625	239.5	6.25	6.05	5.75	1.23	O.K.	1.42	1.44	1.49	6.32	O.K.
A2481	1.315	3.636	232.5	6.05	5.93	5.43	1.20	O.K.	1.43	1.45	1.46	6.23	O.K.

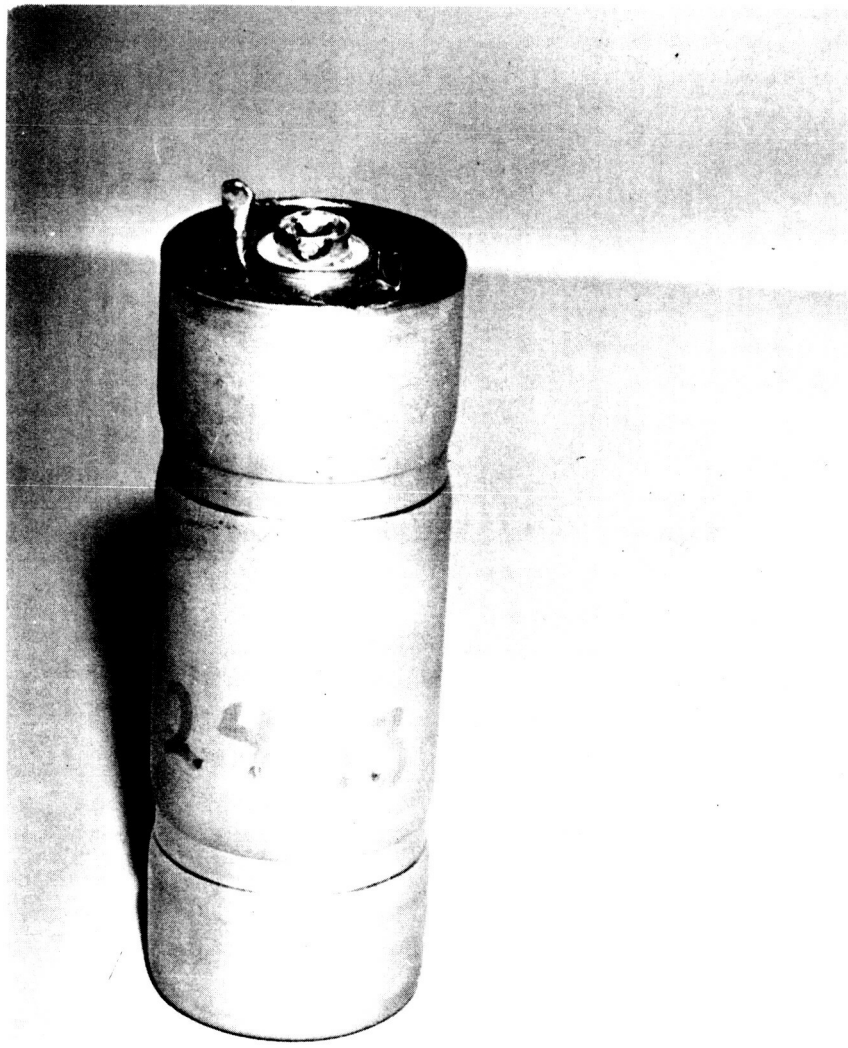

FIGURE 1

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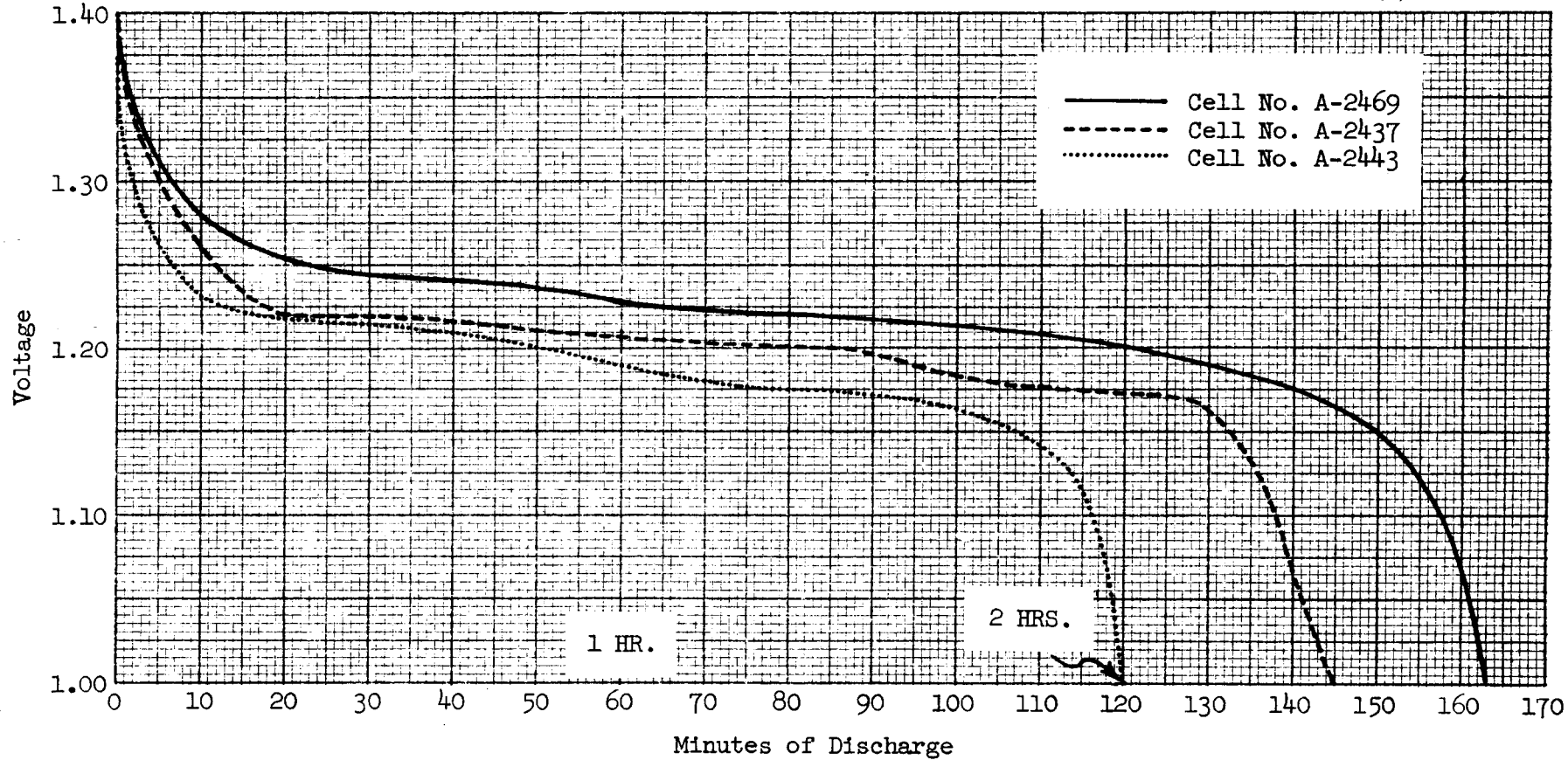
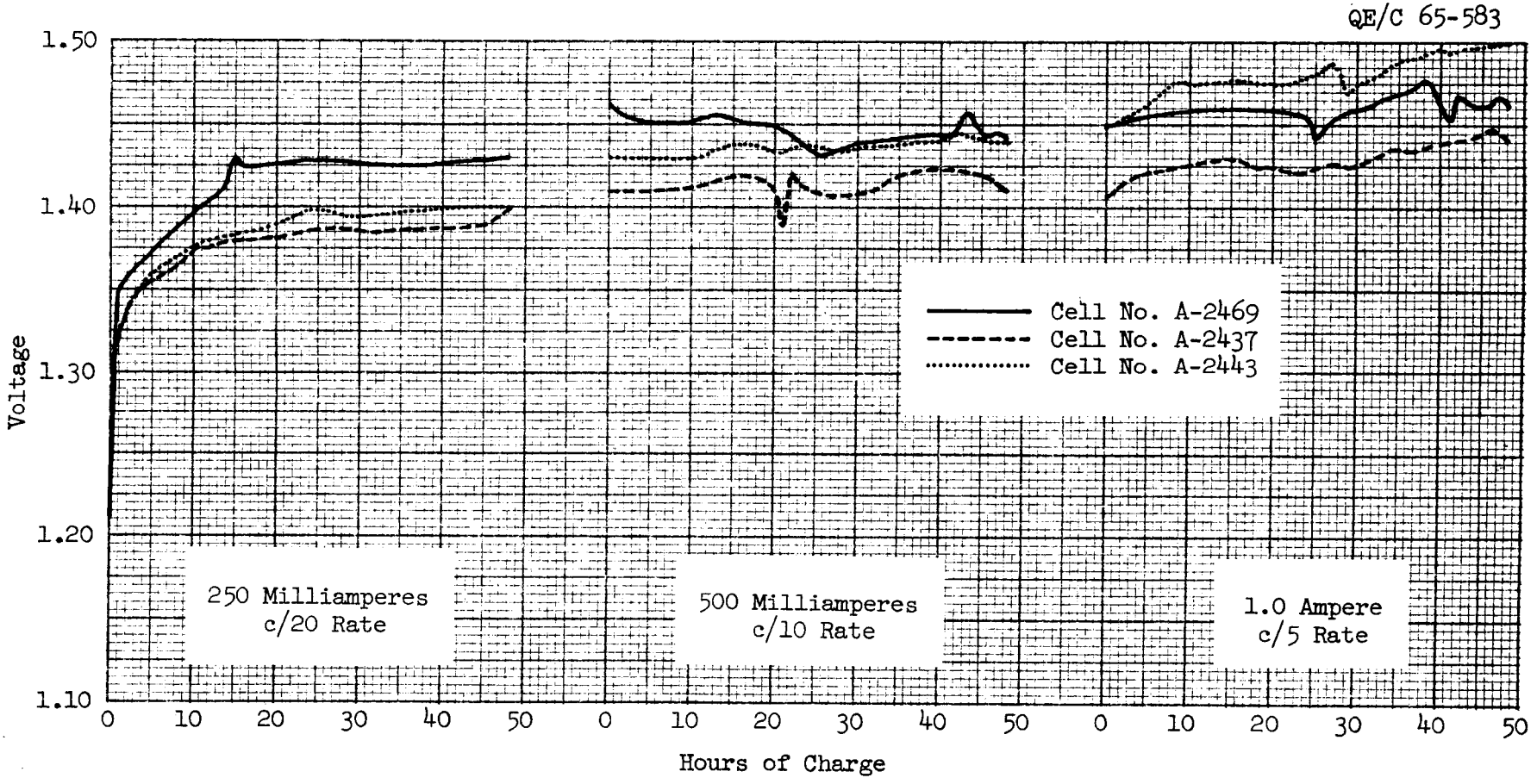


CHARACTERISTIC 2-HOUR RATE DISCHARGE CURVES

SONOTONE 5 AMPERE-HOUR NICKEL CADMIUM SEALED CELLS

FIGURE 2



CHARACTERISTIC 48-HOUR OVERCHARGE CURVES

SONOTONE 5 AMPERE-HOUR NICKEL CADMIUM SEALED CELLS

FIGURE 3

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